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-	55	nail and security and validat\$6 and transmit\$6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB; USOCR	2004/01/21 15:23
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1 Two new techniques for identifying opens on printed circuit boards: analog junction test, and radio frequency induction test

Wrinn, J.;

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 Pages:927

[\[Abstract\]](#) [\[PDF Full-Text \(88 KB\)\]](#) **IEEE CNF**

2 Image mosaicing for rolled fingerprint construction

Ratha, N.K.; Connell, J.H.; Bolle, R.M.;

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3 RF induction and analog junction techniques for finding opens

McElfresh, B.K.;

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